

03560.002732.



PATENT APPLICATION

14/C
5/28/03
D. BEH

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:)
Masato MURAKI et al.) : Examiner: K. Fernandez
Application No.: 09/708,590) : Group Art Unit: 2881
Filed: November 9, 2000) :
For: CORRECTING METHOD FOR) :
CORRECTING EXPOSURE DATA USED) : January 30, 2003
FOR A CHARGED PARTICLE BEAM) :
EXPOSURE SYSTEM) :

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Commissioner for Patents
Washington, D.C. 20231

SUPPLEMENTAL PRELIMINARY AMENDMENT

Sir:

Further to the Request for Continued Examination and the Preliminary Amendment filed on January 28, 2003, and prior to further examination on the merits, please amend the above-identified application as follows:

IN THE CLAIMS

Please AMEND claim 15 and ADD new claims 16-19 as follows. A marked-up copy of the amended claim showing the changes made thereto is attached. Note that all the claims

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